The Role of Frustration in Magnetism of Ge$_{1-x}$Cr$_x$Te Semimagnetic Semiconductor


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PACS: 99.10.Cd

This article was originally published on May 2011 (online on April 2011) with an incorrect version of Fig. 1. The authors apologize for this error. The correct version of Fig. 1 appears below.

![Graph](image-url)

Fig. 1. The magnetization $M$ as a function of temperature for selected Ge$_{0.984}$Cr$_{0.016}$Te crystal measured after cooling sample in the presence (FC) and the absence (ZFC) of the external magnetic field $H$ having four different amplitudes.